Enhancement of J_C-B Properties in MoSi₂ doped MgB₂ tapes

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Abstract:

MoSi₂ doped MgB₂ tapes with different doping levels were prepared through the *in-situ* powder-in-tube method using Fe as the sheath material. Effect of MoSi₂ doping on the MgB₂/Fe tapes was investigated. It is found that the highest J_C value was achieved in the 2.5 at.% doped samples, more than a factor of 4 higher compared to the undoped tapes at 4.2 K, 10 T, then further increasing the doping ratio caused a reduction of J_C. Moreover, all doped tapes exhibited improved magnetic field dependence of Jc. The enhancement of J_C-B properties in MoSi₂ doped MgB₂ tapes is attributed to good grain linkage and the introduction of effective flux pining centers with the doping.

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1. Introduction

The critical current density J_C in MgB₂ has been a central topic for extensive research efforts since superconductivity in this metal compound was discovered [1]. MgB_2 has high superconducting transition temperature (T_C) and does not have weak-link problem at grain boundaries. The material cost of MgB₂ is lower compared to other superconducting materials such as Nb-based superconductors and HTS (High T_C superconductivity) cuprates. Therefore, MgB₂ is a promising candidate for engineering applications at temperatures around 20 K. However, J_C of MgB₂ decreases rapidly under magnetic fields compared to those for the Nb-based superconductors. It is generally agreed that the improvement of J_C can be achieved in two ways: improvement of the grain connectivity and introduction of the effective pining centers [2]. In contrast to HTS, MgB₂ has a relatively large coherence length, and this means that the fluxiods can be pinned by relatively larger particles and precipitates. Accordingly, chemical doping seems to be a very promising way to increase the flux pinning and B_{irr} in MgB₂ [3]. Many works have been done on the chemical doping/additive to MgB₂ [4–11]. Of all these materials, various silicides are very effective on the enhancement of J_C in MgB₂ at high field regime [12, 13, 14]. In this work, a series of MoSi2 doped MgB2 tapes were prepared using an in-situ powder-in-tube (PIT) method. The difference in microstructure and critical current properties induced by various doping level is discussed.

2. Experimental details

MgB₂ tapes were prepared by the *in-situ* PIT method. The sheath materials chosen for this experiment were commercially available pure Fe. Mg (325 mesh, 99.8%), B (2-5 μ m, amorphous, 99.99%), and MoSi₂ (2-5 μ m, 99%) powders were used as the starting material. Mg, B powders were mixed with the nominal composition of 2:1, the MoSi₂ doping levels were 2.5, 5, 10, 15, 20 at.%, respectively. After milling for 1 h, the mixed powder was tightly packed into Fe tubes of 8 mm outside diameter and 1.5 mm wall thickness. The composite tubes were subsequently swaged into rods of 5 mm in diameter, and then the rods were drawn into round wires about 1.5 mm in diameter. Subsequently, the wires were rolled to tapes. The final size

of the tapes was 3.2 mm in width and 0.5 mm in thickness. Undoped tapes were similarly fabricated for comparative study. These tapes were sintered in flowing high purity Ar at 650°C for 1 h, followed by a furnace cooling to room temperature. To the study effects of sintering temperature on $MoSi_2$ doped MgB₂ tapes, samples heated at 750°C for 1 h were also made.

The phase composition and microstructure of the samples were investigated using X-ray diffraction (XRD), energy dispersive x-ray analysis (EDX) and scanning electron microscope (SEM). For SEM/EDX and XRD analysis, rectangular samples were cut from the tapes, and sheath materials were removed. DC magnetization measurement was performed with a superconducting quantum interference device (SQUID) magnetometer, using small pieces of an MgB₂ layer obtained by removing the sheath material of the samples. The T_C was defined as the onset temperature at which a diamagnetic signal was observed. The transport I_C at 4.2 K and its magnetic field dependence were evaluated at the High field laboratory for Superconducting Materials (HFLSM) at Sendai, by a standard four-probe technique, with a criterion of 1 μ V cm⁻¹. Current leads and voltage taps were directly soldered to the sheath materials of the tapes. A magnetic field was applied parallel to the tape surface. The critical current density J_C was obtained by dividing I_C by the cross-sectional area of the MgB₂ core.

3. Results and discussion

Figure 1 exhibits XRD patterns of $MoSi_2$ doped and undoped samples. The XRD pattern for the undoped sample is consistent with the published indices of MgB₂ with a trace amount of MgO. For the 2.5 at.% doped samples, $MoSi_2$ phase is clearly seen as one of main impurities along with MgO. $MoSi_2$ phase can be identified in all the doped samples, and its diffraction peaks are increased with the increase of doping level. There is no observable shift in the peaks of the XRD patterns. This indicates that there were no changes in the lattice parameters between the undoped and $MoSi_2$ doped samples [15]. It is clear that MgB₂ is inert with respect to $MoSi_2$ at 650 \therefore The similar result was also found for WSi₂-doped tapes, as reported by Ma et al [12]. On the contrary, the addition of ZrSi₂ in MgB₂ tapes resulted in the formation of Zr₃Si₂

and Mg₂Si, no diffraction peaks of ZrSi₂ phase was observed, suggesting that there were reaction between MgB₂ and ZrSi₂ [12]. Since Mo and W elements are in the same element group (VIb), their chemical properties are very close, but Zr element is in the IVb group with different crystal structure, electron configuration, bonding radius, et al. This may partially explain different reactivity behavior of MoSi₂ and ZrSi₂ in the corresponding doped samples.

The transition temperatures for the doped and undoped samples determined by DC susceptibility measurements are shown in Fig. 2. T_C obtained as the onset of magnetic screening for the undoped samples was 36.5 K with a transition width of 2 K. For the doped samples, the T_C decreased with increasing the doping level and the transition became broad. However, the degree of T_C depression by MoSi₂ doping is low, indicating that small substitutions occurred in MgB₂ crystal. T_C for the 2.5 % and 5 % doped samples showed little difference, which decreased only 0.5 K compared to the undoped ones, while the T_C for the 15 % doped samples dropped about 2 K with a transition width of 6 K. The broad transition in T_C for the 15 % doped samples may be caused by a large amount of impurities such as MoSi₂, and this is in agreement with the XRD patterns in Fig. 1.

Figure 3 shows the transport current density at 4.2 K in magnetic fields for the undoped and $MoSi_2$ doped samples annealed at 650 . It is noted that the $MoSi_2$ doping not only enhanced the J_C value in magnetic fields but also improved the J_C -B performance. At 2.5 % doping level, the J_C reached 1300 A/cm² at 4.2K,10 T, more than 4-fold improvement compared to the undoped samples, which have a J_C value about 280 A/cm². The J_C value of the MoSi₂ doped samples decreases with further increasing the doping level, but the J_C field dependence does not change. The possible explanation for the decrease of J_C value with increasing the MoSi₂ doping level may be due to the large amount of impurities occurred, which usually lead to weak links at grain boundaries [3], as will be discussed below. On the other hand, the sensitivity of J_C to magnetic field was decreased by the MoSi₂ doping, demonstrating an improved flux pinning ability. This means that effective pining centers such as possible segregates or defects were introduced by the MoSi₂ doping.

The typical images of the fractured core layers for undoped and doped samples are shown in Fig. 4. SEM results clearly revealed that MgB₂ core of the undoped samples was quite porous and loose with some limited melted intergrain regions (see Fig.4a). However, with the addition of 2.5 % MoSi₂ (see Fig.4b), the MgB₂ core has a quite uniform microstructure with fewer voids. It should be noted that although the 15 % doped samples is still rather dense seeing from the SEM image, there are many large particles with a size of 3~5 µm (see Fig.4 c). These large particles had been identified to be MoSi₂ grains by the EDX analysis. The higher the doping level, the more the larger particles scattering within the MgB₂ matrix. This is clearly demonstrated by the evident difference in Mo and Si element contents between the 2.5 % and 15 % doped samples from the insets of Fig. 4. Through the EDX analysis at randomly select area on the MgB₂ core, we found that MoSi₂ ratio is almost identical across the entire sample, suggesting a globally homogeneous phase distribution. As for the 15% doped samples, these largely dispersed MoSi₂ particles, which could decrease the superconducting volume of MgB₂ tapes and weaken the grain linkage, are proposed to be responsible for the reduction of J_C values.

 J_C values vs magnetic filed for the 750 heat-treated samples are plotted in Fig. 5. The J_C -B curve of 2.5% doped samples sintered at 650 was also included. It can be seen that again the J_C -B properties of the MoSi₂ doped samples are improved compared to undoped samples when heated at 750 . Like tapes sintered at 650 (see Fig. 3), the best result was achieved for the 2.5 at.% MoSi₂ additions. J_C was degraded by further additions although it was still higher than the undoped sample. In addition, when comparing the 2.5% doped-samples heated at different temperatures, we can note that the samples annealed at 750 have slightly better field dependence of J_C , implying that a higher sintering temperature leads to more effective flux pinning centers in the doped samples, thus enhancing flux pinning and improving the high-field J_C .

Clearly, our data of $MoSi_2$ doped tapes showed much better J_C -B performance in the whole range of magnetic fields up to 10 T. Good grain linkage had been thought as one of the reasons for the high J_C -B properties in doped tapes. However, as were proved by several groups [9, 14], the grain linkage improvement alone could not explain the lowered field dependence of J_C in doped tapes, since the grain coupling mainly increases the J_C values, hardly changes the field dependence of J_C . There must be more effective flux pinning centers in the doped samples than the undoped tapes. It is speculated that the reaction-induced nanoscale impurities or defects induced by the MoSi₂ doping could act as the strong pinning centers. It should be noted that the size of MoSi₂ particles used was 2-5 µm. In the SiC and C addition, which is significantly effective in increasing J_C in high-field region, nanometer-sized particles were employed [5, 10]. As we know, the surface energy of large particles is much lower than that of nanoscale ones. Thus it is difficult for the micrometer MoSi₂ powders to react with Mg or B and to form nanoscale impurities. Therefore, further improvement in J_C -B performance is expected upon utilization of finer MoSi₂ particles.

4. Conclusions

In summary, we have synthesized $MoSi_2$ doped MgB_2 tapes by the *in-situ* PIT method. The effect of $MoSi_2$ doping on the microstructures and superconducting properties of MgB_2 tapes has been investigated. It is found that the J_C values have been significantly improved by $MoSi_2$ doping. The best result was achieved for the 2.5 at.% $MoSi_2$ additions. J_C was degraded by further additions. Furthermore, the enhanced field dependence of the $MoSi_2$ doping.

Acknowledgments

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Captions

- Figure 1 XRD patterns of in-situ processed undoped and all MoSi₂ doped tapes heated at 650 for 1 h. The peaks of MgB₂ indexed, while the peaks of MgO and MoSi₂ are marked by asterisks and circles, respectively.
- Figure 2 The temperature dependence of the DC magnetic susceptibility curves of the $MoSi_2$ doped and undoped tapes.
- Figure 3 J_C -B properties of Fe-sheathed undoped and MoSi₂ doped tapes heated at 650 for 1 h.
- Figure 4 SEM images of the undoped (a), 2.5% (b), and 15% (c) MoSi₂ doped samples after peeling off the Fe sheath.
- Figure 5 J_C -B properties of Fe-sheathed undoped and MoSi₂ doped tapes heated at 750 for 1 h. J_C -B curve of 2.5% doped samples heated at 650 was also included.

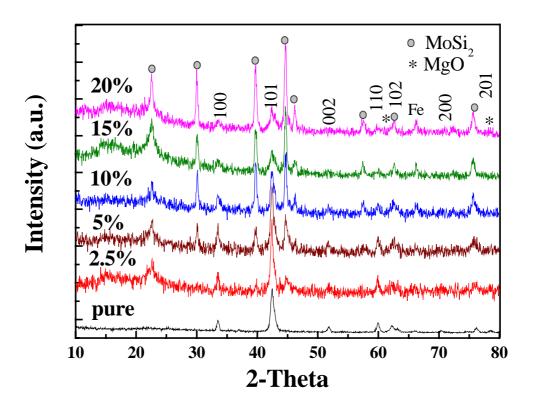


Fig.1 Zhang et al.

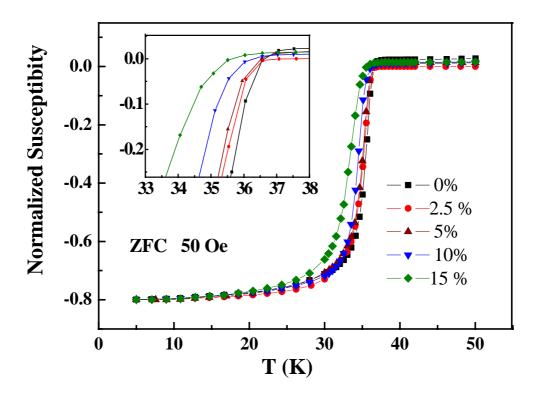


Fig 2 Zhang et al.

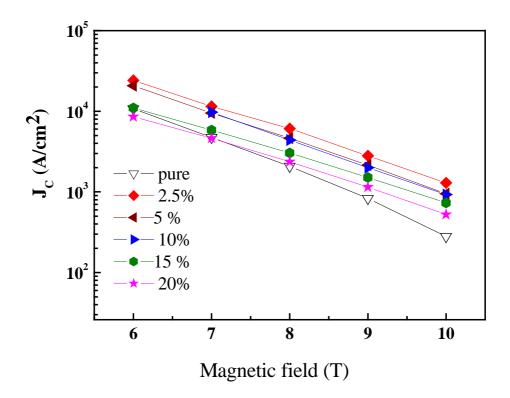


Fig 3 Zhang et al.

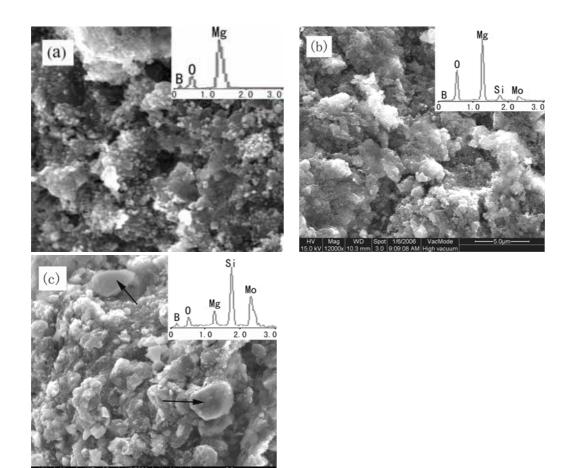


Fig 4 Zhang et al.

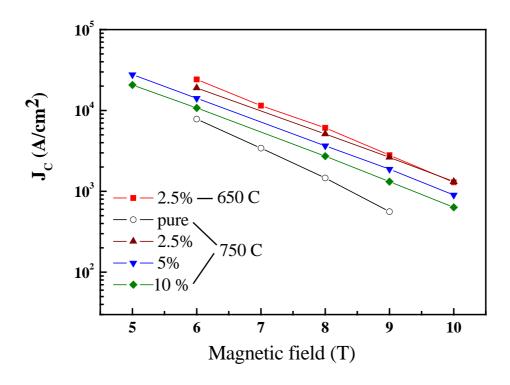


Fig 5 Zhang et al.